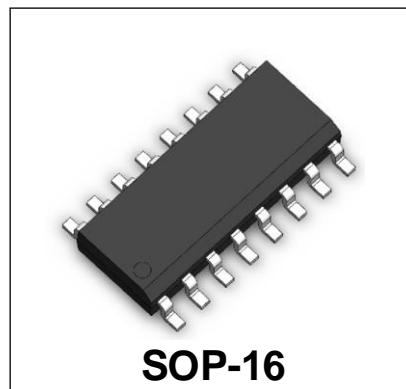



**WLN2003A**
**HIGH VOLTAGE, HIGH CURRENT  
DARLINGTON TRANSISTOR ARRAYS**

## Description

The WLN2003A are high voltage, high current Darlington arrays each containing seven open collector common emitter pairs. Each pair is rated at 500mA. Suppression diodes are included for inductive load driving, the inputs and outputs are pinned in opposition to simplify board layout.



## Features

- ESD Capability: 8KV(HBM)
- 500mA Rated Collector Current (Single Output)
- High Voltage Outputs: 50V
- Output Clamp Diodes
- Inputs Compatible with Popular Logic Types (5V TTL,CMOS)
- Relay Driver Applications

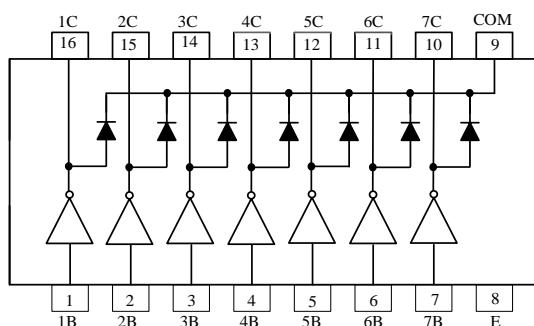
## Mechanical Characteristics

- JEDEC SOP-16 package
- Marking: Marking Code
- Packaging: Tape and Reel
- RoHS Compliant & HF
- Device meets MSL3 requirement

## Applications

- Solenoids
- Relays
- DC motors
- LED displays
- Filament lamps
- Thermal print-heads
- High-power buffers

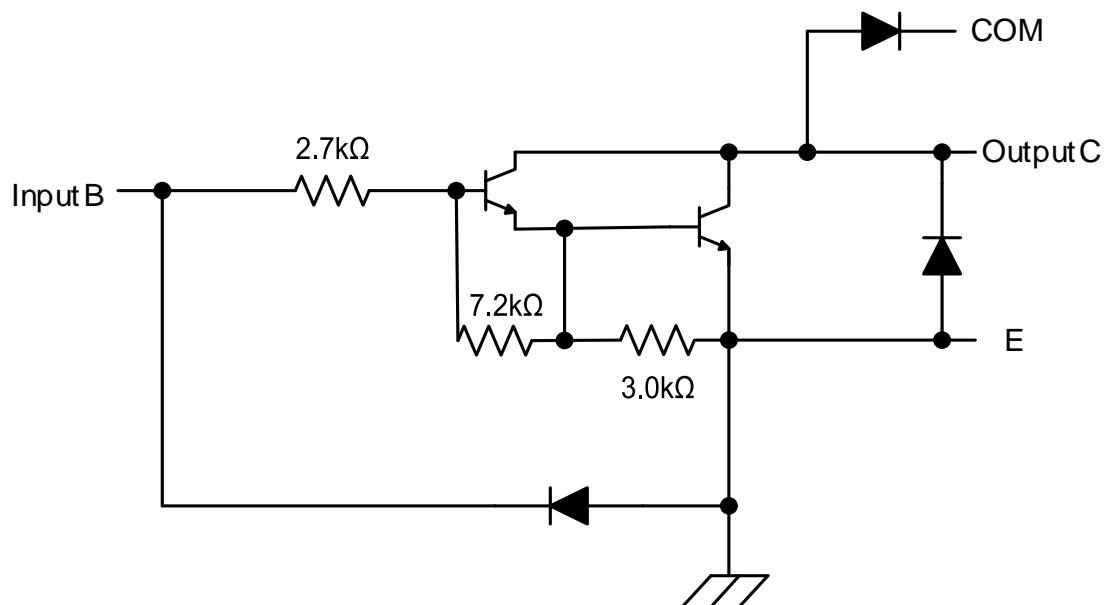
## Functional Diagram


**SOP-16 (Top View)**

## Pin Descriptions

Pin Number	Pin Name	Function
1	1B	Input Pair 1
2	2B	Input Pair 2
3	3B	Input Pair 3
4	4B	Input Pair 4
5	5B	Input Pair 5
6	6B	Input Pair 6
7	7B	Input Pair 7
8	E	Common Emitter (Ground)
9	COM	Common Clamp Diodes
10	7C	Output Pair 7
11	6C	Output Pair 6
12	5C	Output Pair 5
13	4C	Output Pair 4
14	3C	Output Pair 3
15	2C	Output Pair 2
16	1C	Output Pair 1

## Functional Block Diagram



**Absolute Maximum Ratings** (Note 1) (@TA = +25°C, unless otherwise specified.)

Symbol	Parameter	Rating	Unit
V <sub>CC</sub>	Collector to Emitter Voltage	50	V
V <sub>R</sub>	Clamp Diode Reverse Voltage (Note 2)	50	V
V <sub>I</sub>	Input Voltage (Note 2)	30	V
I <sub>CP</sub>	Peak Collector Current	500	mA
I <sub>OK</sub>	Output Clamp Current	500	mA
I <sub>TE</sub>	Total Emitter Current	-2.5	A
θ <sub>JA</sub>	Thermal Resistance Junction-to-Ambient (Note 3)	63.0	°C/W
θ <sub>JC</sub>	Thermal Resistance Junction-to-Case (Note 4)	12.0	°C/W
P <sub>D</sub>	Power Dissipation (Note 5)	1.38	W
T <sub>J</sub>	Junction Temperature	+150	°C
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C

## Notes:

1. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only. Functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.
3. Maximum power dissipation is a function of T<sub>J(max)</sub>, θ<sub>JA</sub> and T<sub>A</sub>. The maximum allowable power dissipation at any allowable ambient temperature is P<sub>D</sub> = (T<sub>J(max)</sub> – T<sub>A</sub>)/θ<sub>JA</sub>. Operating at the absolute maximum T<sub>J</sub> of +150°C can affect reliability.
4. Maximum power dissipation is a function of T<sub>J(max)</sub>, θ<sub>JC</sub> and T<sub>A</sub>. The maximum allowable power dissipation at any allowable ambient temperature is P<sub>D</sub> = (T<sub>J(max)</sub> – T<sub>C</sub>)/θ<sub>JC</sub>. Operating at the absolute maximum T<sub>J</sub> of +150°C can affect reliability.
5. On PCB (Test Board: JEDEC 2s2p)

**Recommended Operating Conditions**

Symbol	Parameter	MIN	MAX	Unit
V <sub>CC</sub>	Collector to Emitter Voltage	-	50	V
T <sub>A</sub>	Operating Ambient Temperature	-40	+105	°C

**Switching Characteristics** (@TA = +25°C, unless otherwise specified.)

Parameter		Test Figure	Min	Typ	Max	Unit
t <sub>PLH</sub>	Propagation Delay Time, Low to High Level Output	9	-	0.25	1	μs
t <sub>PHL</sub>	Propagation Delay Time, High to Low Level Output	9	-	0.25	1	μs
V <sub>OH</sub>	High Level Output Voltage after Switching	9 (V <sub>S</sub> = 50V, I <sub>O</sub> = 300mA)	V <sub>S</sub> -20	-	-	mV

**Switching Characteristics** (@TA = -40 to +105°C, unless otherwise specified.)

Parameter		Test Figure	Min	Typ	Max	Unit
t <sub>PLH</sub>	Propagation Delay Time, Low to High Level Output	9	-	1	10	μs
t <sub>PHL</sub>	Propagation Delay Time, High to Low Level Output	9	-	1	10	μs
V <sub>OH</sub>	High Level Output Voltage after Switching	9 (V <sub>S</sub> = 50V, I <sub>O</sub> = 300mA)	V <sub>S</sub> -50	-	-	mV

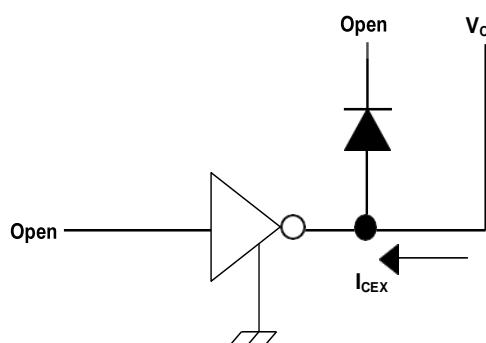
## Electrical Characteristics (Cont.) (@TA = +25°C, unless otherwise specified.)

Parameter		Test Figure	Test Conditions		Min	Typ	Max	Unit
$V_{I(ON)}$	On State Input Voltage	6	$V_{CE} = 2V$	$I_C = 200mA$	-	-	2.4	V
				$I_C = 250mA$	-	-	2.7	
				$I_C = 300mA$	-	-	3	
$V_{CE(SAT)}$	Collector Emitter Saturation Voltage	5	$I_I = 250\mu A, I_C = 100mA$		-	0.9	1.1	V
			$I_I = 350\mu A, I_C = 200mA$		-	1	1.3	
			$I_I = 500\mu A, I_C = 350mA$		-	1.2	1.6	
$V_F$	Clamp Forward Voltage	8	$I_F = 350mA$		-	1.7	2	V
Hfe	DC Current Transfer Ratio	5	$V_{ce}=2V, I_C=350mA$		1000			
$I_{CEX}$	Collector Cut-off Current	1	$V_{CE} = 50V, I_I = 0$		-	-	50	$\mu A$
		2	$V_{CE} = 50V, T_A = +105^\circ C$		$I_I = 0$	-	-	
$I_{I(OFF)}$	Off State Input Current	3	$V_{CE} = 50V, I_C = 500\mu A$		50	65	-	$\mu A$
$I_I$	Input Current	4	$V_I = 3.85V$		-	0.93	1.35	mA
$I_R$	Clamp Reverse Current	7	$V_R = 50V$	$T_A = +105^\circ C$	-	-	100	$\mu A$
		-		-	-	-	50	
$C_I$	Input Capacitance	-	$V_I = 0, f = 1MHz$		-	15	25	pF

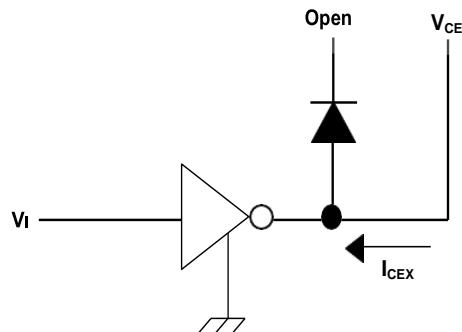
## Electrical Characteristics (Cont.) (@TA = -40°C to +105°C, unless otherwise specified.)

Parameter		Test Figure	Test Conditions		Min	Typ	Max	Unit
$V_{I(ON)}$	On State Input Voltage	6	$V_{CE} = 2V$	$I_C = 200mA$	-	-	2.7	V
				$I_C = 250mA$	-	-	2.9	
				$I_C = 300mA$	-	-	3	
$V_{CE(SAT)}$	Collector Emitter Saturation Voltage	5	$I_I = 250\mu A, I_C = 100mA$		-	0.9	1.2	V
			$I_I = 350\mu A, I_C = 200mA$		-	1	1.4	
			$I_I = 500\mu A, I_C = 350mA$		-	1.2	1.7	
$V_F$	Clamp Forward Voltage	8	$I_F = 350mA$		-	1.7	2.2	V
$I_{CEX}$	Collector Cut-off Current	1	$V_{CE} = 50V, I_I = 0$		-	-	100	$\mu A$
$I_{I(OFF)}$	Off State Input Current	3	$V_{CE} = 50V, I_C = 500\mu A$		30	65	-	$\mu A$
$I_I$	Input Current	4	$V_I = 3.85V$		-	0.93	1.35	mA
$I_R$	Clamp Reverse Current	7	$V_R = 50V$		-	-	100	$\mu A$
$C_I$	Input Capacitance	-	$V_I = 0, f = 1MHz$		-	15	25	pF

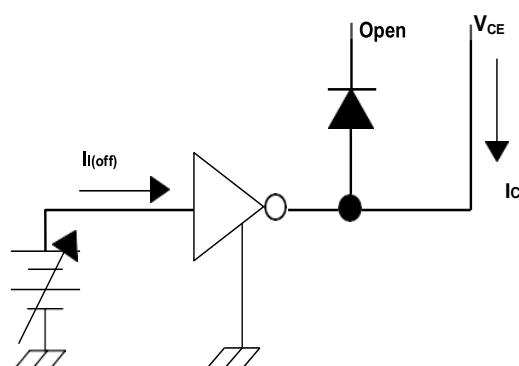
## Parameter Measurement Circuits



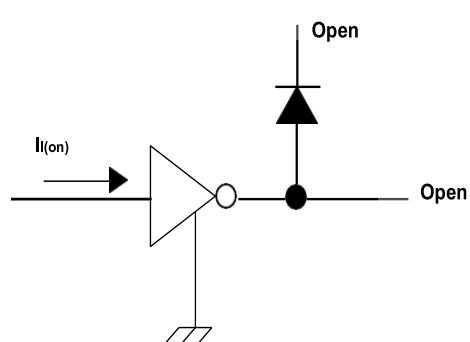
**Fig.1**  $I_{CEx}$  Test Circuit



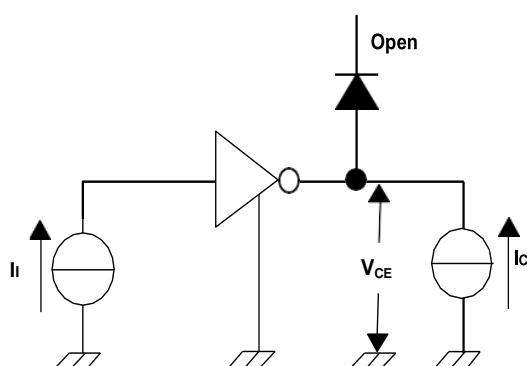
**Fig.2**  $I_{CEx}$  Test Circuit



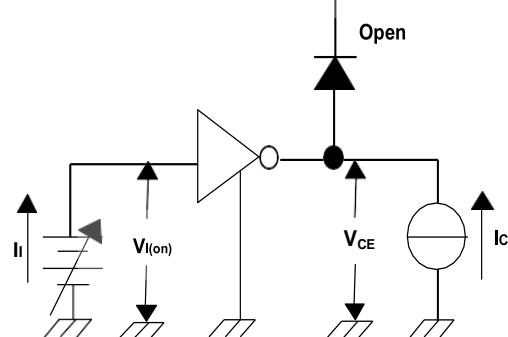
**Fig.3**  $I_{l(off)}$  Test Circuit



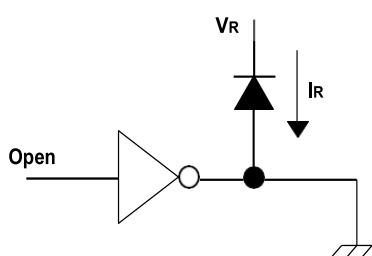
**Fig.4**  $I_l$  Test Circuit



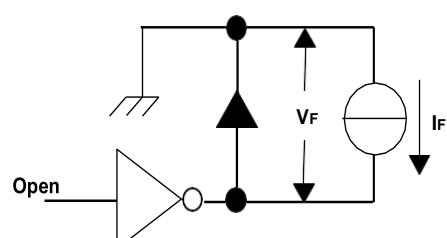
**Fig.5**  $h_{FE}$ ,  $V_{CE(sat)}$  Test Circuit



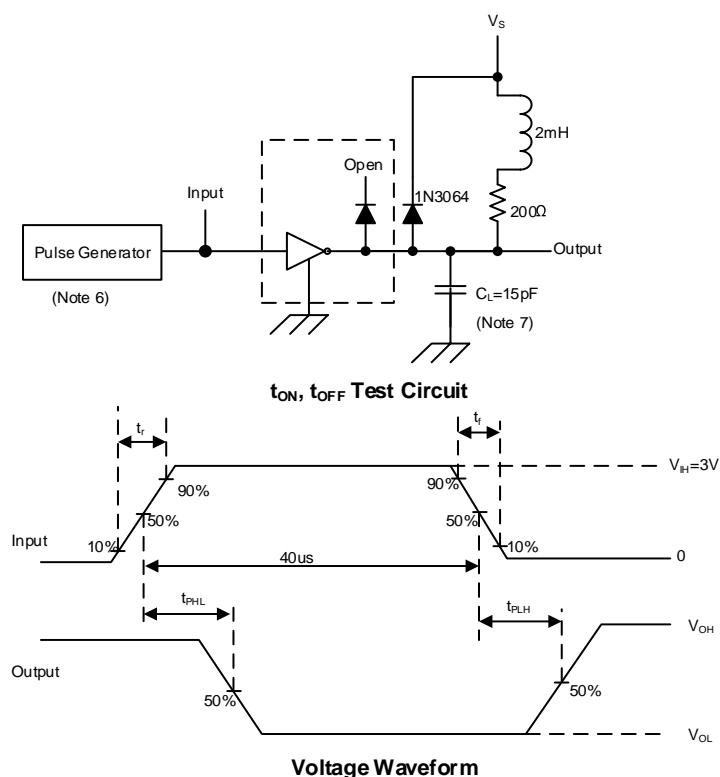
**Fig.6**  $V_{l(on)}$  Test Circuit



**Fig.7**  $I_R$  Test Circuit



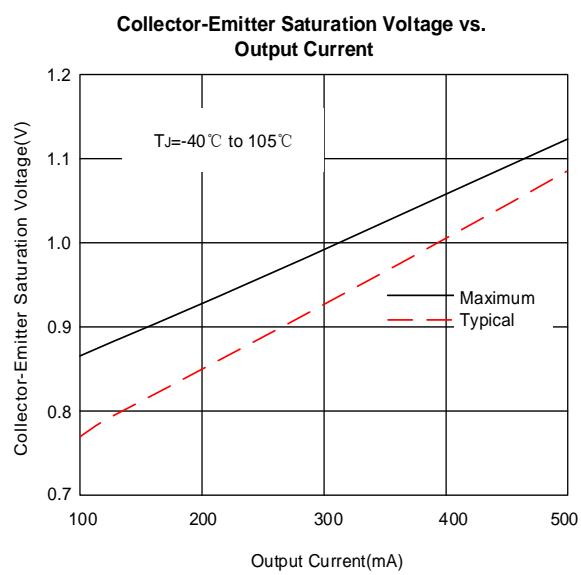
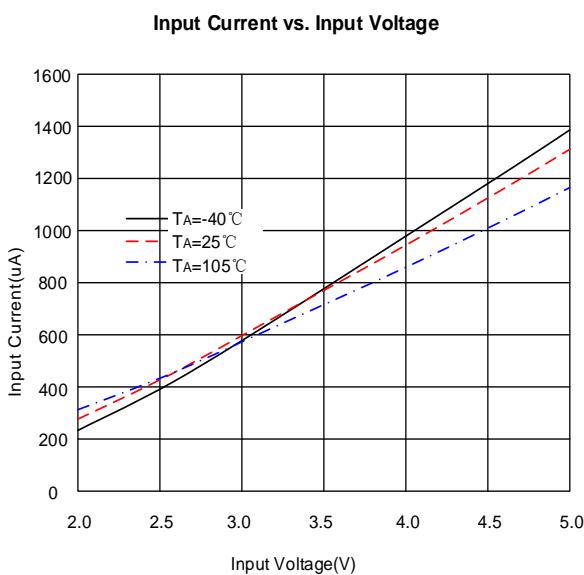
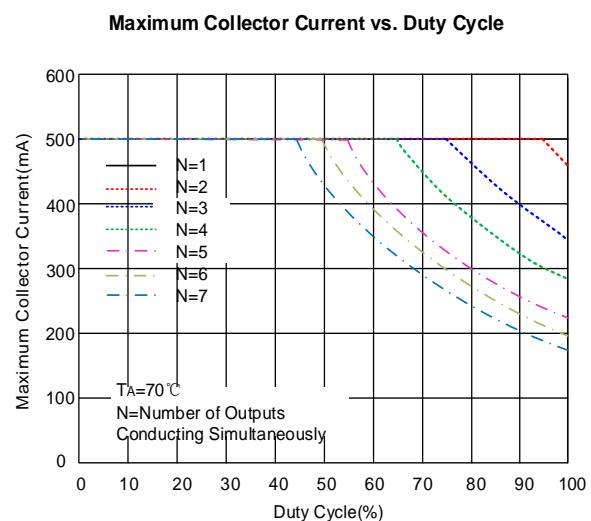
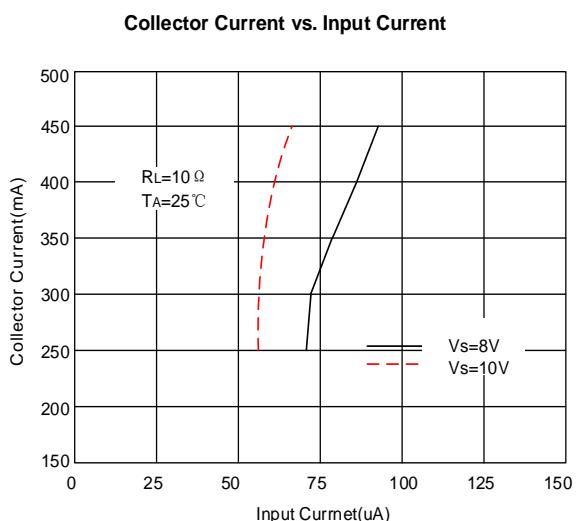
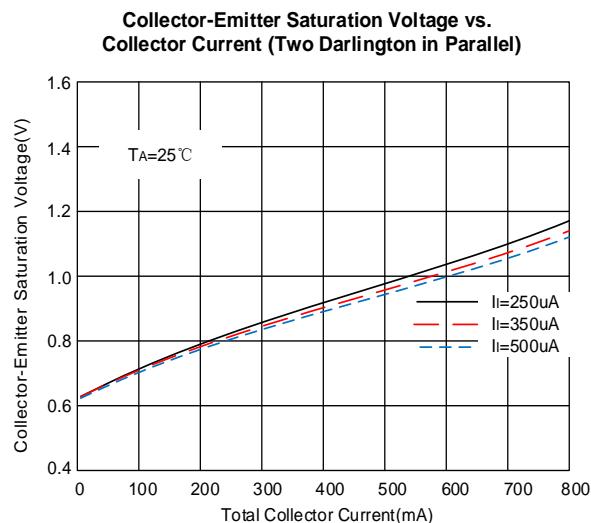
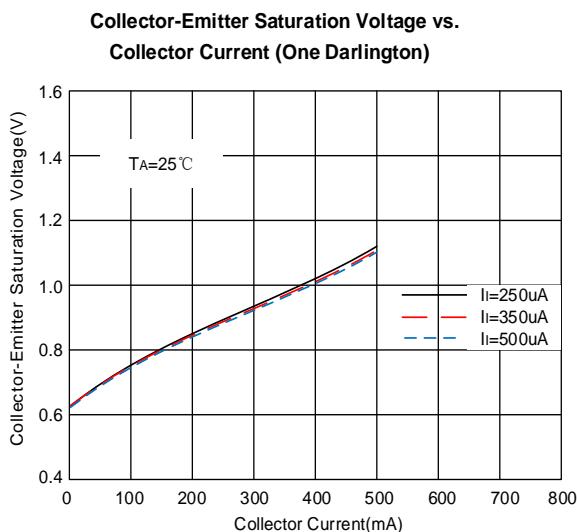
**Fig.8**  $V_F$  Test Circuit

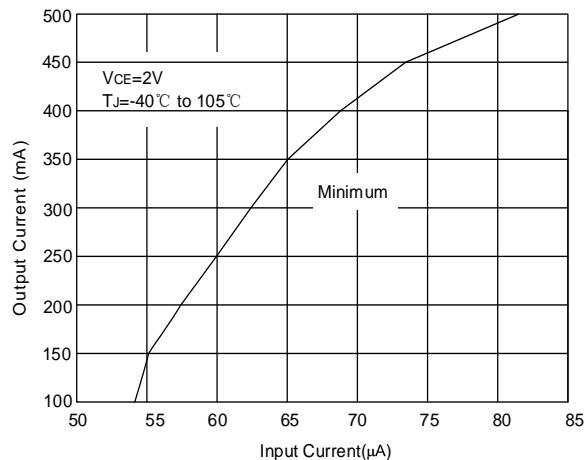
**Parameter Measurement Circuits (Cont.)**

**Fig. 9 Latch-Up Test Circuit and Voltage Waveform**
**Notes:**

6 The pulse generator has the following characteristics: Pulse Width = 12.5Hz, output impedance  $50\Omega$ ,  $t_r \leq 5\text{ns}$ ,  $t_f \leq 10\text{ns}$ .

7  $C_L$  includes probe and jig capacitance.

## Typical Performance Characteristics



**Output Current vs. Input Current**

## Outline Drawing – SOP-16

PACKAGE OUTLINE			
Symbol	MILLIMETERS		
	MIN	NOM	MAX
A	-	-	1.75
A1	0.10	0.15	0.225
A2	1.30	1.45	1.50
A3	0.60	0.65	0.70
b	0.33	-	0.47
c	0.2	-	0.24
D	9.50	9.90	10.05
E	5.80	6.00	6.20
E1	3.80	3.90	4.00
e	1.27 BSC		
L	0.50	0.60	0.80
L1	1.10 BSC		
θ1	8°	-	15°
θ2	8°	-	15°
θ3	8°	-	15°
θ4	8°	-	15°
θ5	0°	-	8°

Soldering Footprint		DIM	MILLIMETERS
		C	5.60
		G	3.80
		P	1.27
		X	0.47
		Y	1.8
		Z	7.40

## Marking Codes

Part Number	WLN2003A
Marking Code	 WLN2003A-Specific Device Code XXXX-Lot Code

## Package Information

Qty: 2.5k/Reel

## CONTACT INFORMATION

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WAYON website: <http://www.way-on.com>

For additional information, please contact your local Sales Representative.

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Specifications are subject to change without notice.  
 The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.  
 Users should verify actual device performance in their specific applications.